

# TESSA – introduction, applications and road map

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## **X-FEL for industrial processes**

- X-ray FELs are established as research tools
- Can X-FEL become manufacturing/industrial tools?



#### Semiconductor industry roadmap



LE	LE $\rightarrow$ immersion $\rightarrow$ LE <sup>2</sup> $\rightarrow$ SADP $\rightarrow$ SAQP	LE
248 nm	193 nm laser	13.5 nm



- Multi-patterning is too expensive to maintain Moore's law past n10
- EUV lithography can fill the gap



#### **EUVL source challenge**

- EUV lithography @ 13.5 nm is the most economic solution beyond N10
- Power per scanner: 250 W for insertion, 1 kW at full capacity
- LPP limiting factors: debris mitigation, heat management, CW CO2 lasers
- It is expected that LPP will reach 250 W, but not kW
- LPP are expensive: ~ \$70 M each
- FEL can offer non-granular solution (10-30 kW CW FEL to power the entire foundry)



E. R. Hosler *et al* "Considerations for a free-electron laser-based extreme-ultraviolet lithography program", Proc. of SPIE **9422**, 94220D-1 (2015).



# **Industry consolidation**

- A cost of modern HVM fab facility ~ \$10 billion
- 4 companies consolidated most of the high end market
- 1 company (ASML) dominates tools market
- Presumably in 2012 ASML initiated internal EUV FEL R&D program (presently on hold)



ASML is at the center of the industry ecosystem for over a decade



## **10 kW class FEL topology options and risks**

**Energy Recovery Linac (ERL) FEL** 



Leveraged on Jlab design and 10 kW IR ERL FEL

Closed system, has to be developed and tested in its entirety High injected/recirculated current, machine protection is an issue

**Untested physics of short wavelength ERL FEL** 

Very elegant solution to reducing the RF power and beam dump costs



Extensive practical experience with single pass X-FEL, large pool of experts and trained personnel

Well developed modeling tools

Untested physics of high efficiency short wavelength FEL

Modular design, enables future upgrades, also testing can be done in existing facilities

(pictures courtesy of J. Byrd, LBNL)

# **FEL efficiency**

- SASE efficiency is limited to Pierce parameter (~ 0.1% at EUV)
- Conventional adiabatic tapering: keep the bunched beam in phase and let it radiate; efficiency per length is usually about the same (~1 MeV/m for EUV)
- Conventional tapered FEL efficiency is limited by de-bunching, sidebands, and practical undulator length



#### **IFEL experience**

- IFEL demonstrated energy exchange rate ~ 100 MeV/m
- Strong seed + strong tapering = high gradient
- There is no media losses, the process should be reversible
- IFEL in reverse = TESSA

(Tapering Enhanced <u>Stimulated</u> Superradiant Amplification)



In an IFEL the electron beam absorbs energy from a radiation field.



UCLA results from RUBICON experiments J. Duris et al, *Nature Comm.* **5**, 4928, 2014

# **TESSA vs. Tapered FEL**

- Large seed intensity (above SASE saturation intensity)
- Fast deceleration through stimulated emission (> 10 MeV/m)
- Strong taper (period by period optimization)
- Possibility of >50% efficiency in a relatively short interaction distance



# **TESSA roadmap**

- Applications are at EUV (possibly THz), and also at very high powers (> MW)
- 10 μm TESSA decelerator successful (UCLA experiments, 2015-2016), UCLA program is ongoing
- Next steps (2017-2019):
  - Demonstration of TESSA amplifier (lower seed energy)
  - Experimental study of wavelength scaling

[can be done at LEA beamline, topic of this workshop]

- Beyond the next steps:
  - Short wavelengths (no seeds and poor mirrors)
  - TESSA oscillator
  - Integration with superconducting RF

[migration to Fermilab]